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# FQD10N20C / FQU10N20C

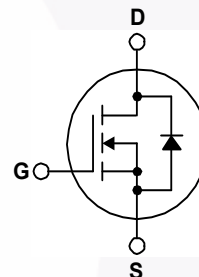
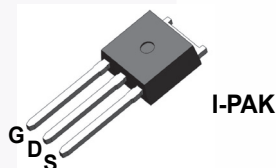
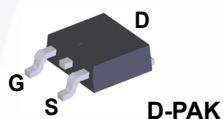
## N-Channel QFET® MOSFET 200 V, 7.8 A, 360 mΩ

### Features

- 7.8 A, 200 V,  $R_{DS(on)} = 360 \text{ m}\Omega$  (Max.) @  $V_{GS} = 10 \text{ V}$ ,  $I_D = 3.9 \text{ A}$
- Low Gate Charge (Typ. 20 nC)
- Low  $C_{rss}$  (Typ. 40.5 pF)
- 100% Avalanche Tested

### Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.



### Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted.

Symbol	Parameter	FQD10N20CTM / FQU10N20CTU	Unit
$V_{DSS}$	Drain-Source Voltage	200	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ )	7.8	A
	- Continuous ( $T_C = 100^\circ\text{C}$ )	5.0	A
$I_{DM}$	Drain Current - Pulsed (Note 1)	31.2	A
$V_{GSS}$	Gate-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	210	mJ
$I_{AR}$	Avalanche Current (Note 1)	7.8	A
$E_{AR}$	Repetitive Avalanche Energy (Note 1)	5.0	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ (Note 3)	5.5	V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ )	50	W
	- Derate above $25^\circ\text{C}$	0.4	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

### Thermal Characteristics

Symbol	Parameter	FQD10N20CTM / FQU10N20CTU	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	2.5	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	110	

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQD10N20C	FQD10N20CTM	D-PAK	330 mm	16 mm	2500 units
FQU10N20C	FQU10N20CTU	I-PAK	Tube	N/A	70 units

## Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Off Characteristics						
$V_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	200	--	--	V
$\frac{\Delta V_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$ , Referenced to 25°C	--	0.28	--	V/°C
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 200\text{ V}, V_{GS} = 0\text{ V}$	--	--	10	$\mu\text{A}$
		$V_{DS} = 160\text{ V}, T_C = 125^\circ\text{C}$	--	--	100	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 30\text{ V}, V_{DS} = 0\text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -30\text{ V}, V_{DS} = 0\text{ V}$	--	--	-100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	2.0	--	4.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 3.9\text{ A}$	--	0.29	0.36	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 40\text{ V}, I_D = 3.9\text{ A}$	--	5.6	--	S
Dynamic Characteristics						
$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	395	510	pF
$C_{oss}$	Output Capacitance		--	97	125	pF
$C_{rss}$	Reverse Transfer Capacitance		--	40.5	53	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 100\text{ V}, I_D = 9.5\text{ A},$ $R_G = 25\text{ }\Omega$  (Note 4)	--	11	30	ns
$t_r$	Turn-On Rise Time		--	92	190	ns
$t_{d(off)}$	Turn-Off Delay Time		--	70	150	ns
$t_f$	Turn-Off Fall Time		--	72	160	ns
$Q_g$	Total Gate Charge	$V_{DS} = 160\text{ V}, I_D = 9.5\text{ A},$ $V_{GS} = 10\text{ V}$  (Note 4)	--	20	26	nC
$Q_{gs}$	Gate-Source Charge		--	3.1	--	nC
$Q_{gd}$	Gate-Drain Charge		--	10.5	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
$I_S$	Maximum Continuous Drain-Source Diode Forward Current		--	--	7.8	A
$I_{SM}$	Maximum Pulsed Drain-Source Diode Forward Current		--	--	31.2	A
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 7.8\text{ A}$	--	--	1.5	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{ V}, I_S = 9.5\text{ A},$	--	158	--	ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F / dt = 100\text{ A}/\mu\text{s}$	--	0.97	--	$\mu\text{C}$

### NOTES:

1. Repetitive Rating : Pulse width limited by maximum junction temperature.
2.  $L = 5.2\text{ mH}$ ,  $I_{AS} = 7.8\text{ A}$ ,  $V_{DD} = 50\text{ V}$ ,  $R_G = 25\text{ }\Omega$ , starting  $T_J = 25^\circ\text{C}$ .
3.  $I_{SD} \leq 9.5\text{ A}$ ,  $di/dt \leq 300\text{ A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , starting  $T_J = 25^\circ\text{C}$ .
4. Essentially independent of operating temperature.

## Typical Characteristics

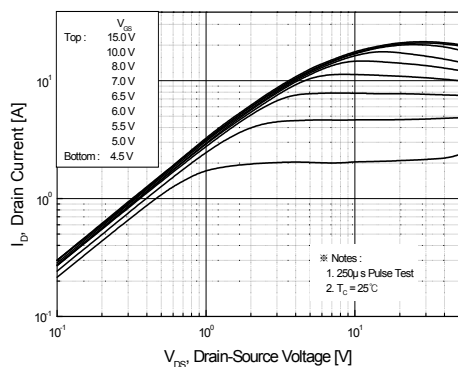


Figure 1. On-Region Characteristics

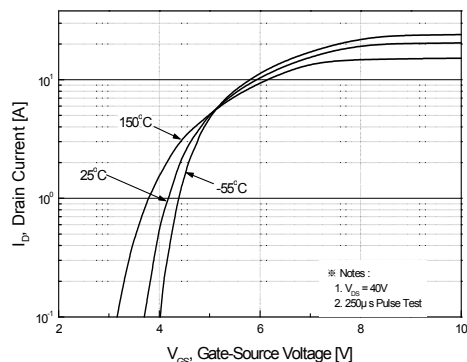


Figure 2. Transfer Characteristics

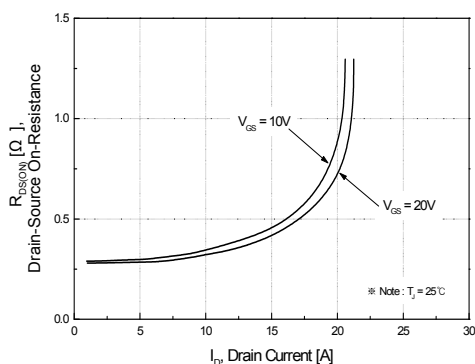


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

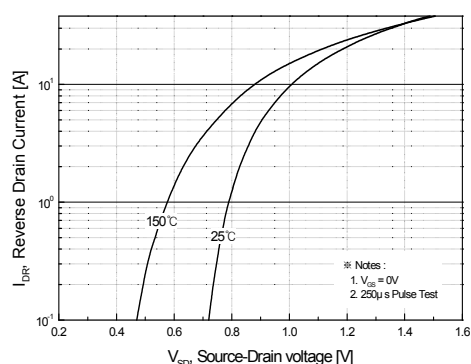


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

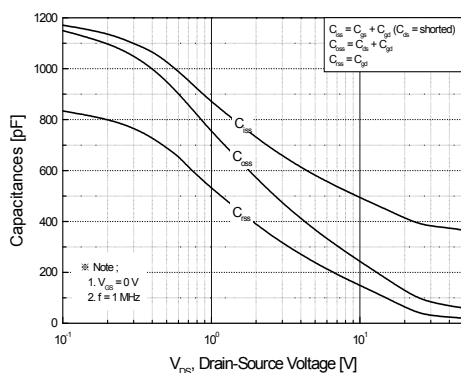


Figure 5. Capacitance Characteristics

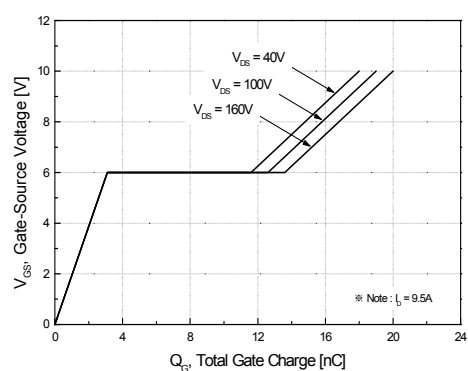
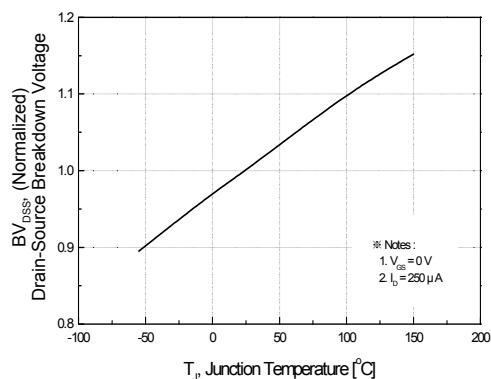
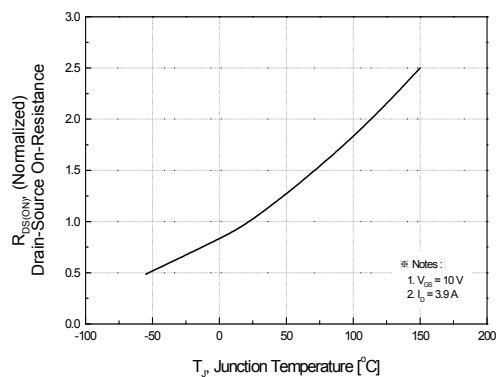


Figure 6. Gate Charge Characteristics

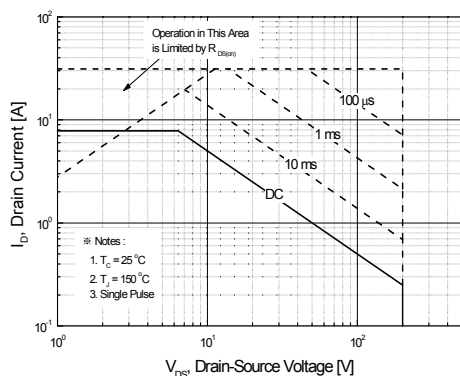
# Typical Characteristics (Continued)



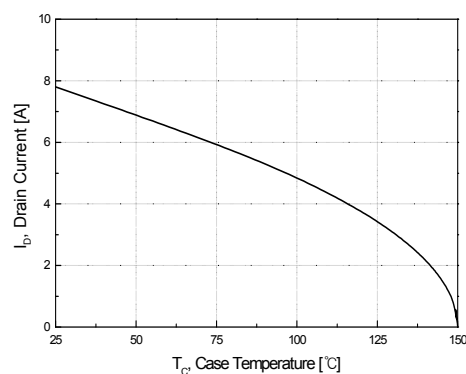
**Figure 7. Breakdown Voltage Variation vs Temperature**



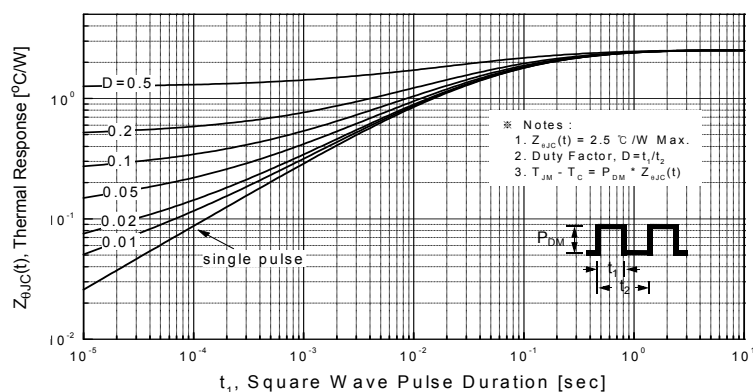
**Figure 8. On-Resistance Variation vs Temperature**



**Figure 9. Maximum Safe Operating Area**

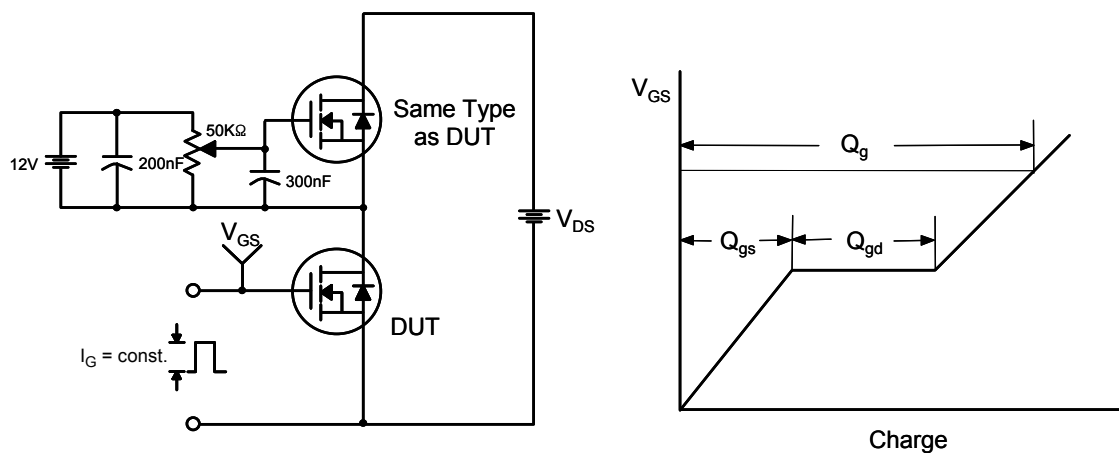


**Figure 10. Maximum Drain Current vs Case Temperature**

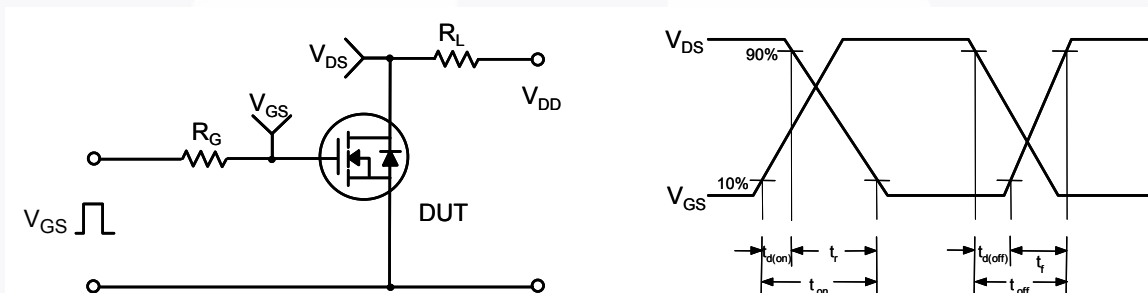


**Figure 11. Transient Thermal Response Curve**

**Figure 12. Gate Charge Test Circuit & Waveform**



**Figure 13. Resistive Switching Test Circuit & Waveforms**



**Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms**

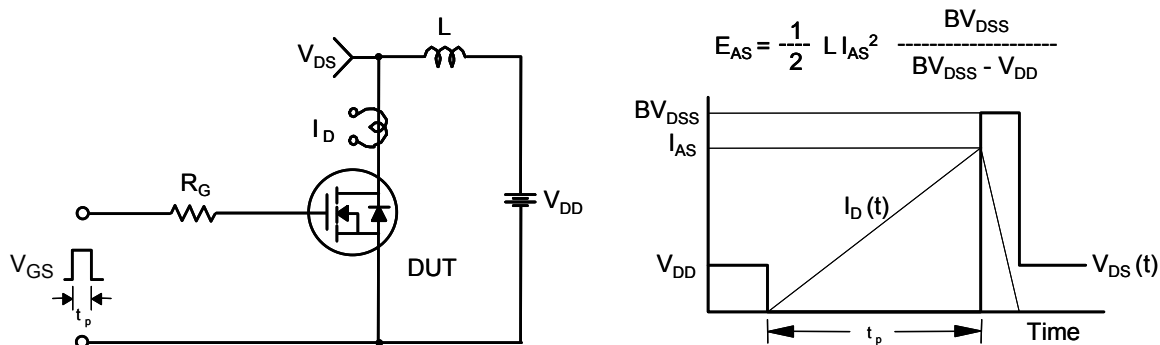
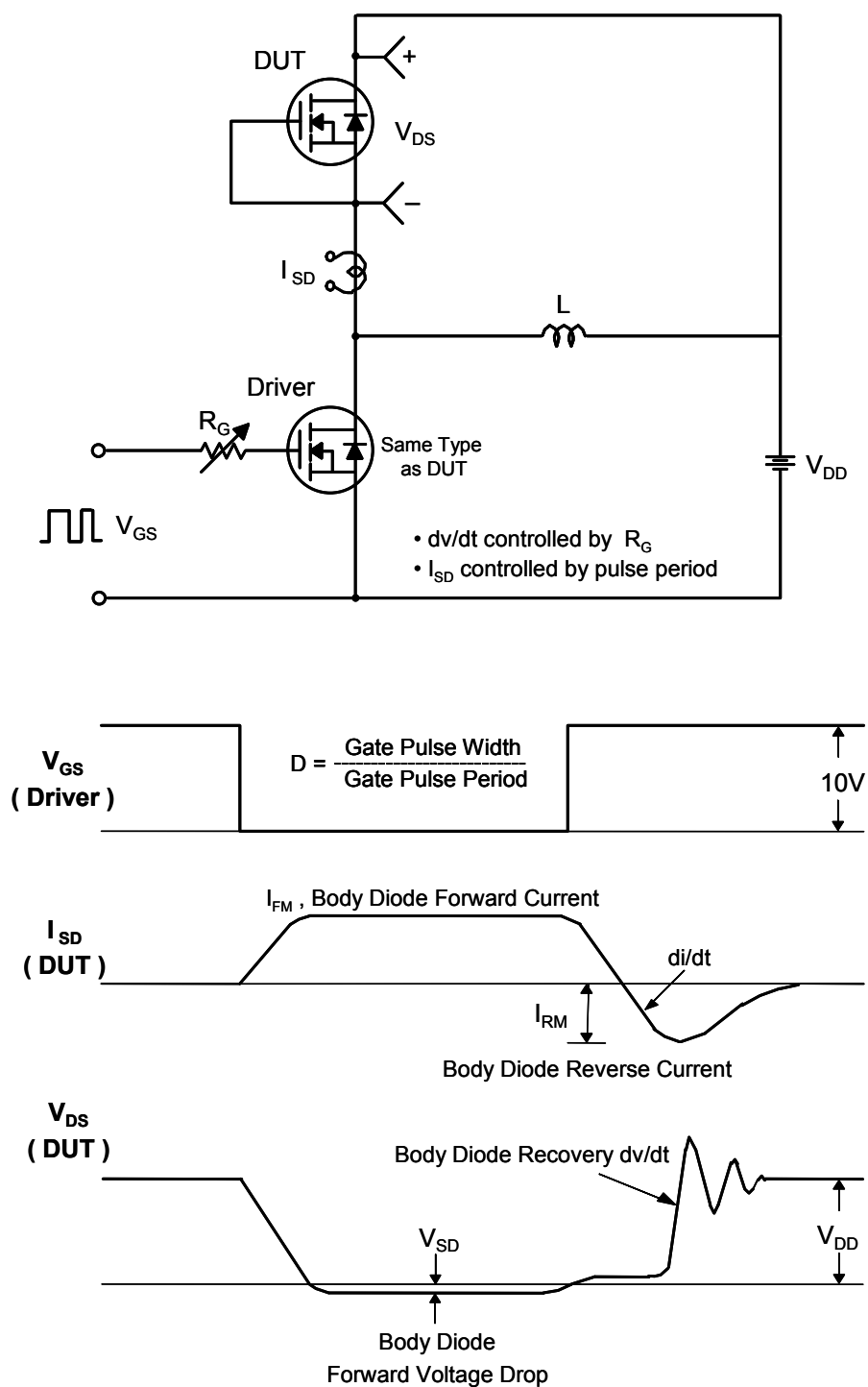
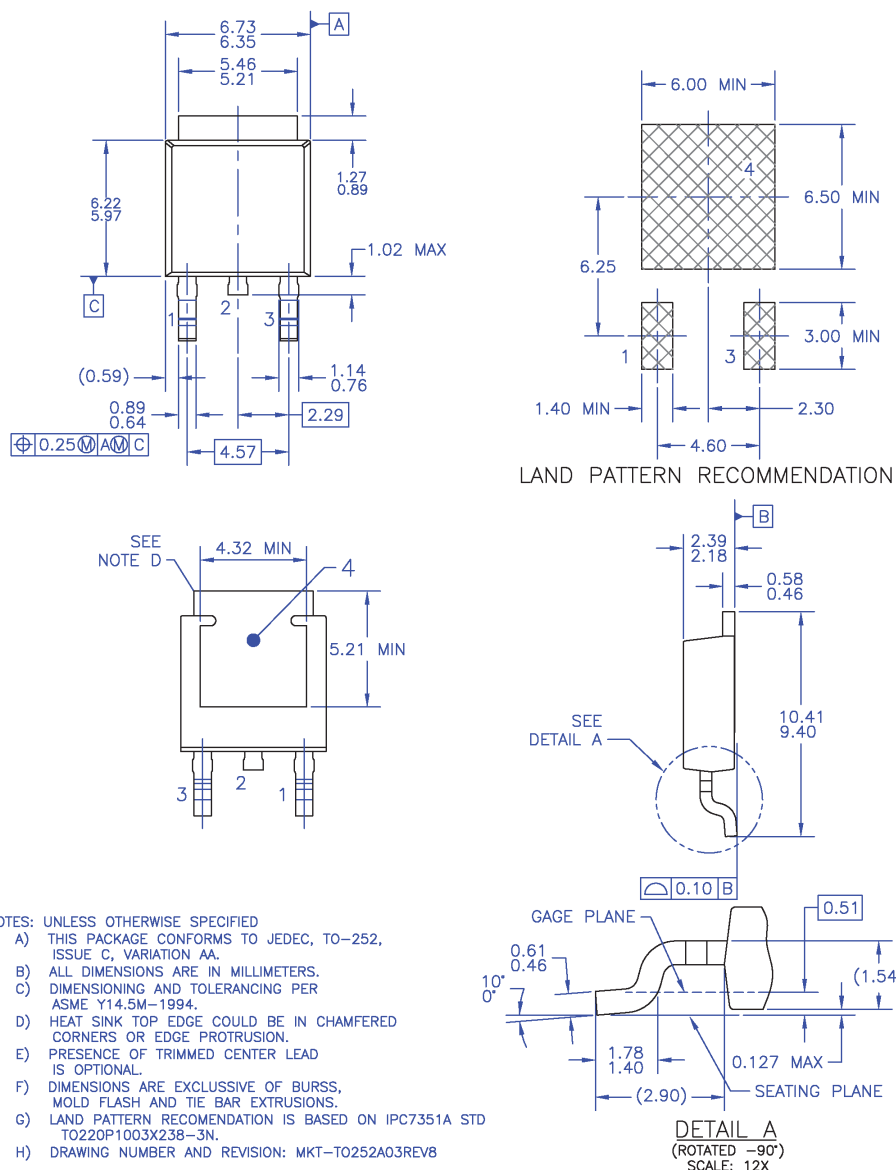


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



## Mechanical Dimensions

### TO-252 3L (DPAK)



**Figure 16. TO252 (D-PAK), Molded, 3 Lead, Option AA&AB**

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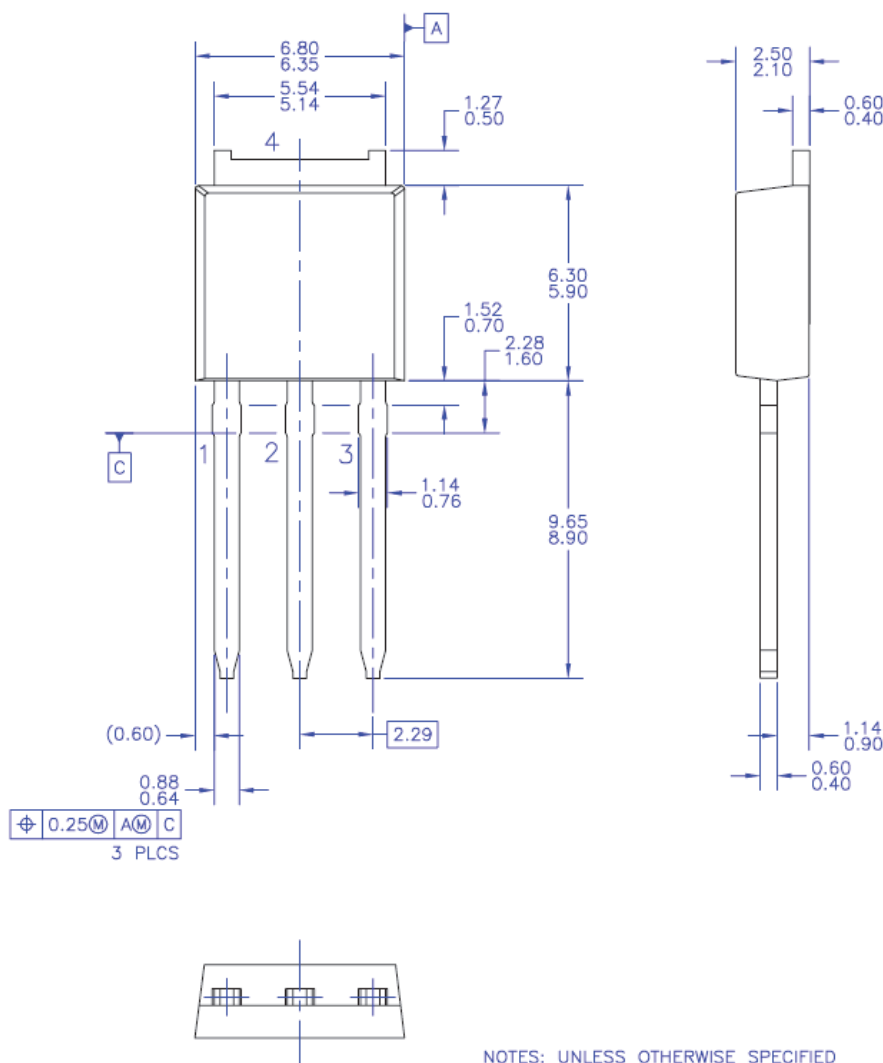
[http://www.fairchildsemi.com/package/packageDetails.html?id=PN\\_TT252-003](http://www.fairchildsemi.com/package/packageDetails.html?id=PN_TT252-003)

Dimension in Millimeters



## Mechanical Dimensions

## TO-251 3L (IPAK)



NOTES: UNLESS OTHERWISE SPECIFIED

- A) ALL DIMENSIONS ARE IN MILLIMETERS.  
B) THIS PACKAGE CONFORMS TO JEDEC, TO-251,  
ISSUE C, VARIATION AA, DATED SEP 1988.  
C) DIMENSIONING AND TOLERANCING PER  
ASME Y14.5M-1994.

**Figure 17. TO251 (IPAK) Molded 3 Lead**

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Dimension in Millimeters



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